



Docket No.: A8319.0034/P034
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshiaki Nagashima, et al.

Examiner: John E. Chapman, Jr.

Application No.: 10/780,751

Art Unit: 2856

Filed: February 19, 2004

For: NONDESTRUCTIVE INSPECTION
APPARATUS AND NONDESTRUCTIVE
INSPECTION METHOD USING ELASTIC
GUIDED WAVE

AMENDMENT

Commissioner for Patents

MS: Amendment

P.O. Box 1450

Alexandria, VA 22313-1450

Dear Sir:

This paper is in response to the Office Action dated June 14, 2005. Please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 11 of this paper.

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